



国晶微半导体
Gwok Semiconductor



Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitances
- Easy to Parallel and Simple to Drive
- Avalanche Ruggedness
- Halogen Free, RoHS Compliant

Benefits

- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

Applications

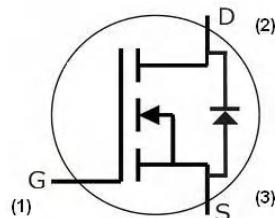
- Solar Inverters
- Switch Mode Power Supplies
- High Voltage DC/DC Converters
- Battery Chargers
- Motor Drives
- Pulsed Power applications

| Part Number | Package |
|--------------|----------|
| GC2M0080120D | TO-247-3 |

| | |
|--------------------|--------|
| V_{DS} | 1200 V |
| $I_D @ 25^\circ C$ | 36 A |
| $R_{DS(on)}$ | 80 mΩ |



TO-247-3
Package



Maximum Ratings ($T_c = 25^\circ C$ unless otherwise specified)

| Symbol | Parameter | Value | Unit | Test Conditions | Note |
|----------------|--|-------------|--------------|---|---------|
| V_{DSmax} | Drain - Source Voltage | 1200 | V | $V_{GS} = 0 V, I_D = 100 \mu A$ | |
| V_{GSmax} | Gate - Source Voltage | -10/+25 | V | Absolute maximum values | |
| V_{GSop} | Gate - Source Voltage | -5/+20 | V | Recommended operational values | |
| I_D | Continuous Drain Current | 36 | A | $V_{GS} = 20 V, T_c = 25^\circ C$ | Fig. 19 |
| | | 24 | | $V_{GS} = 20 V, T_c = 100^\circ C$ | |
| $I_{D(pulse)}$ | Pulsed Drain Current | 80 | A | Pulse width t_P limited by T_{jmax} | Fig. 22 |
| P_D | Power Dissipation | 192 | W | $T_c=25^\circ C, T_j = 150^\circ C$ | Fig. 20 |
| T_j, T_{stg} | Operating Junction and Storage Temperature | -55 to +150 | °C | | |
| T_L | Solder Temperature | 260 | °C | 1.6mm (0.063") from case for 10s | |
| M_d | Mounting Torque | 1 8.8 | Nm lbf-in | M3 or 6-32 screw | |



Electrical Characteristics ($T_c = 25^\circ C$ unless otherwise specified)

| Symbol | Parameter | Min. | Typ. | Max. | Unit | Test Conditions | Note |
|---------------|----------------------------------|------|------|------|-----------|---|-----------------|
| $V_{(BR)DSS}$ | Drain-Source Breakdown Voltage | 1200 | | | V | $V_{GS} = 0 V, I_D = 100 \mu A$ | |
| $V_{GS(th)}$ | Gate Threshold Voltage | 2.0 | 2.9 | 4 | V | $V_{DS} = V_{GS}, I_D = 5 mA$ | Fig. 11 |
| | | | 2.4 | | V | $V_{DS} = V_{GS}, I_D = 5 mA, T_J = 150^\circ C$ | |
| I_{DSS} | Zero Gate Voltage Drain Current | | 1 | 100 | μA | $V_{DS} = 1200 V, V_{GS} = 0 V$ | |
| I_{GSS} | Gate-Source Leakage Current | | | 250 | nA | $V_{GS} = 20 V, V_{DS} = 0 V$ | |
| $R_{DS(on)}$ | Drain-Source On-State Resistance | | 80 | 98 | $m\Omega$ | $V_{GS} = 20 V, I_D = 20 A$ | Fig. 4, 5, 6 |
| | | | 144 | | | $V_{GS} = 20 V, I_D = 20 A, T_J = 150^\circ C$ | |
| g_{fs} | Transconductance | | 10 | | S | $V_{DS} = 20 V, I_{DS} = 20 A$ | Fig. 7 |
| | | | 9 | | | $V_{DS} = 20 V, I_{DS} = 20 A, T_J = 150^\circ C$ | |
| C_{iss} | Input Capacitance | | 1130 | | pF | $V_{GS} = 0 V$ | Fig. 17, 18 |
| C_{oss} | Output Capacitance | | 92 | | | $V_{DS} = 1000 V$ | |
| C_{rss} | Reverse Transfer Capacitance | | 7.5 | | μJ | $f = 1 MHz$ | Fig. 16 |
| E_{oss} | C_{oss} Stored Energy | | 50 | | | $V_{AC} = 25 mV$ | |
| E_{AS} | Avalanche Energy, Single Pulse | | 1 | | J | $I_D = 20 A, V_{DD} = 50 V$ | Fig. 29 |
| E_{ON} | Turn-On Switching Energy | | 523 | | μJ | $V_{DS} = 800 V, V_{GS} = -5/20 V, I_D = 20 A, R_{G(ext)} = 2.5 \Omega, L = 156 \mu H$ | Fig. 25 |
| E_{OFF} | Turn Off Switching Energy | | 72 | | | | |
| $t_{d(on)}$ | Turn-On Delay Time | | 15 | | ns | $V_{DD} = 800 V, V_{GS} = -5/20 V, I_D = 20 A, R_{G(ext)} = 2.5 \Omega, R_L = 40 \Omega, \text{Timing relative to } V_{DS}$ Per IEC60747-8-4 pg 83 | Fig. 27 |
| t_r | Rise Time | | 22 | | | | |
| $t_{d(off)}$ | Turn-Off Delay Time | | 24 | | | | |
| t_f | Fall Time | | 14 | | | | |
| $R_{G(int)}$ | Internal Gate Resistance | | 3.9 | | Ω | $f = 1 MHz, V_{AC} = 25 mV$ | |
| Q_{gs} | Gate to Source Charge | | 17 | | nC | $V_{DS} = 800 V, V_{GS} = -5/20 V, I_D = 20 A$ Per IEC60747-8-4 pg 21 | Fig. 12 |
| Q_{gd} | Gate to Drain Charge | | 29 | | | | |
| Q_g | Total Gate Charge | | 71 | | | | |

Reverse Diode Characteristics

| Symbol | Parameter | Typ. | Max. | Unit | Test Conditions | Note |
|-----------|----------------------------------|------|------|------|--|------------------|
| V_{SD} | Diode Forward Voltage | 4.3 | | V | $V_{GS} = -5 V, I_{SD} = 10 A$ | Fig. 8, 9, 10 |
| | | 3.8 | | V | $V_{GS} = -5 V, I_{SD} = 10 A, T_J = 150^\circ C$ | |
| I_S | Continuous Diode Forward Current | | 36 | A | $T_c = 25^\circ C$ | Note 1 |
| t_{rr} | Reverse Recover time | 24 | | ns | $V_{GS} = -5 V, I_{SD} = 20 A, V_R = 800 V$ $dif/dt = 1950 A/\mu s$ | Note 1 |
| Q_{rr} | Reverse Recovery Charge | 152 | | nC | | |
| I_{rrm} | Peak Reverse Recovery Current | 10 | | A | | |

Note (1): When using SiC Body Diode the maximum recommended $V_{GS} = -5 V$

Thermal Characteristics

| Symbol | Parameter | Typ. | Max. | Unit | Test Conditions | Note |
|-----------|---|------|------|--------------|-----------------|---------|
| R_{iJC} | Thermal Resistance from Junction to Case | 0.60 | 0.65 | $^\circ C/W$ | | Fig. 21 |
| R_{iJA} | Thermal Resistance From Junction to Ambient | | 40 | | | |



Typical Performance

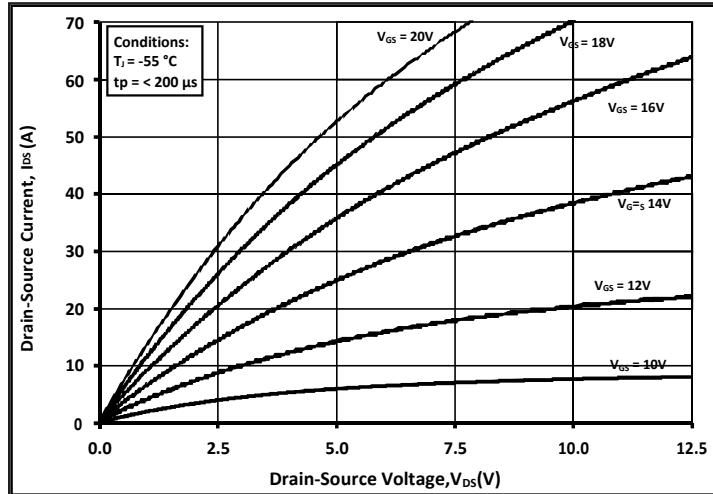


Figure 1. Output Characteristics $T_J = -55^\circ\text{C}$

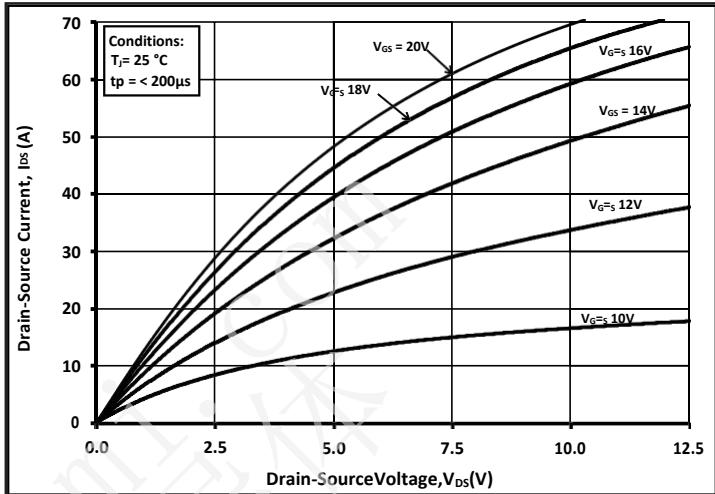


Figure 2. Output Characteristics $T_J = 25^\circ\text{C}$

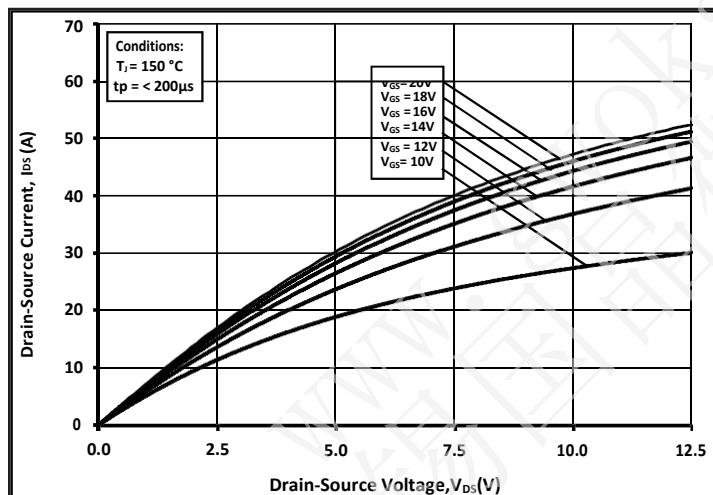


Figure 3. Output Characteristics $T_J = 150^\circ\text{C}$

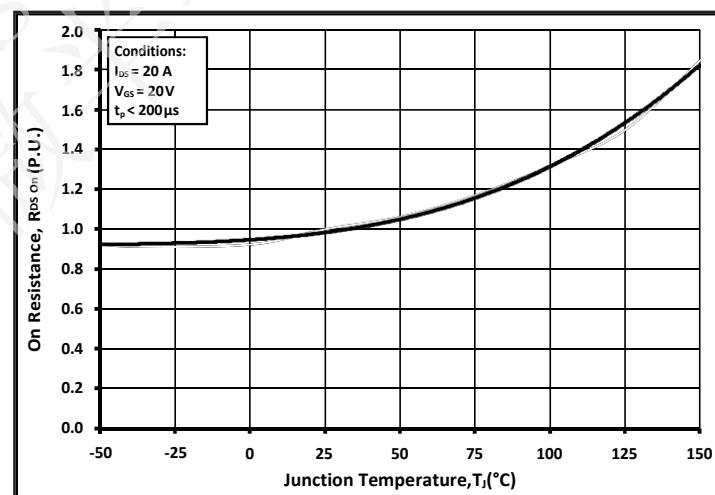


Figure 4. Normalized On-Resistance vs. Temperature

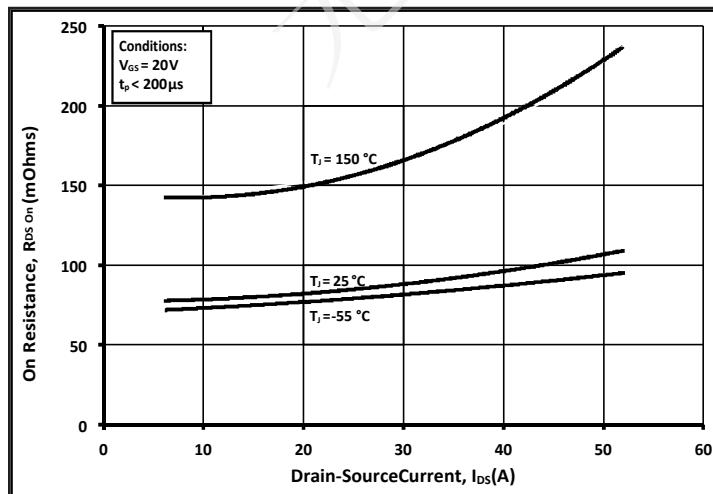


Figure 5. On-Resistance vs. Drain Current
For Various Temperatures

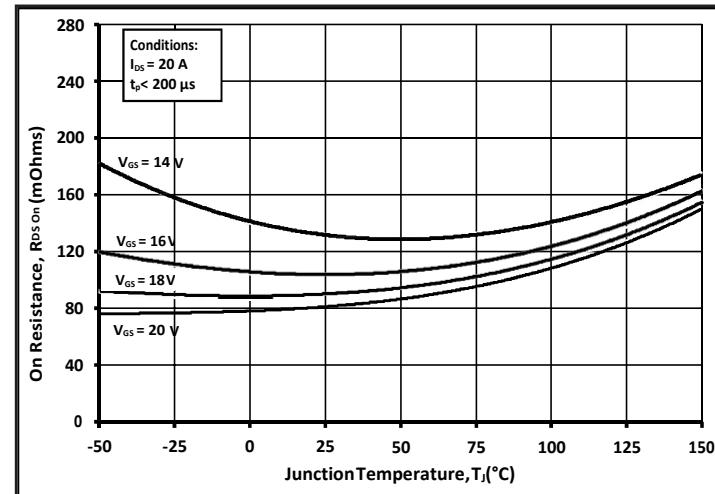


Figure 6. On-Resistance vs. Temperature
For Various Gate Voltage



Typical Performance

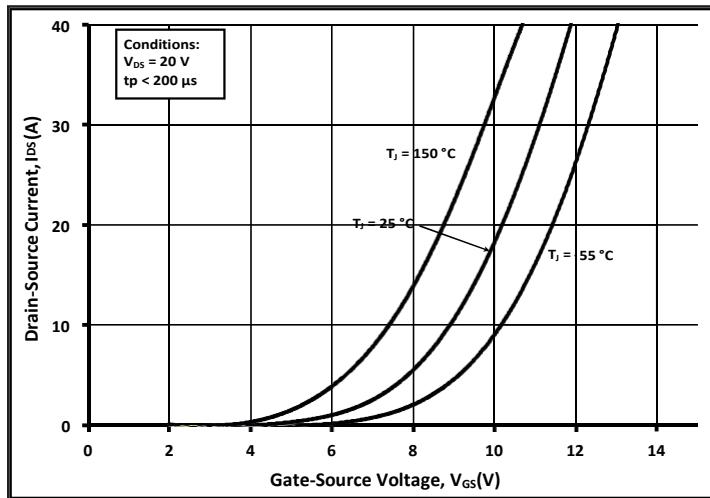


Figure 7. Transfer Characteristic for Various Junction Temperatures

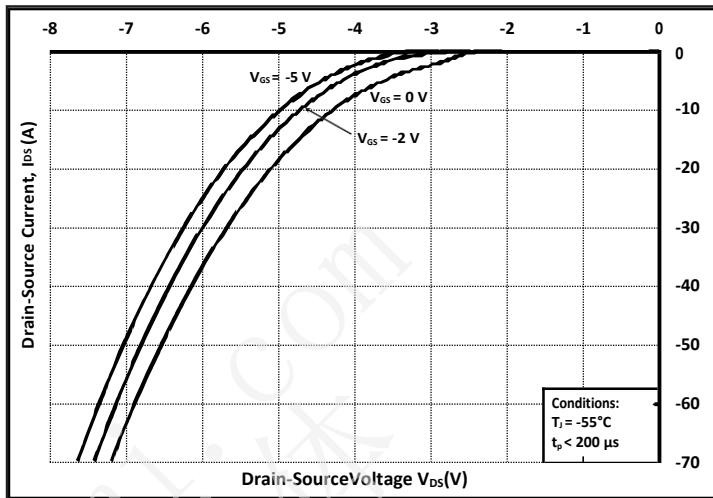


Figure 8. Body Diode Characteristic at -55°C

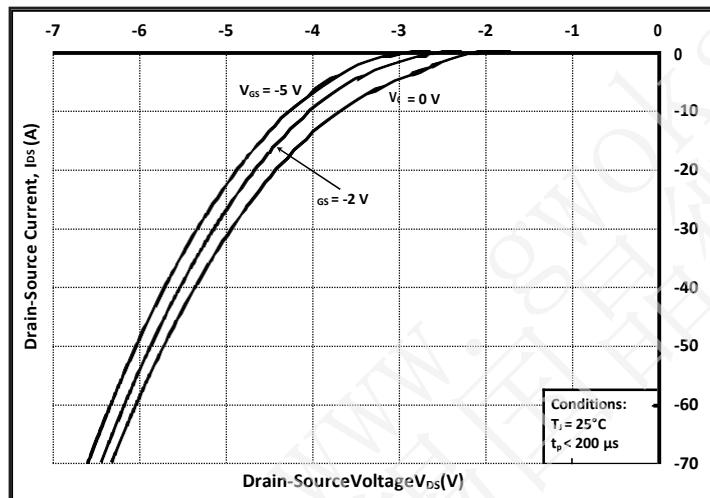


Figure 9. Body Diode Characteristic at 25°C

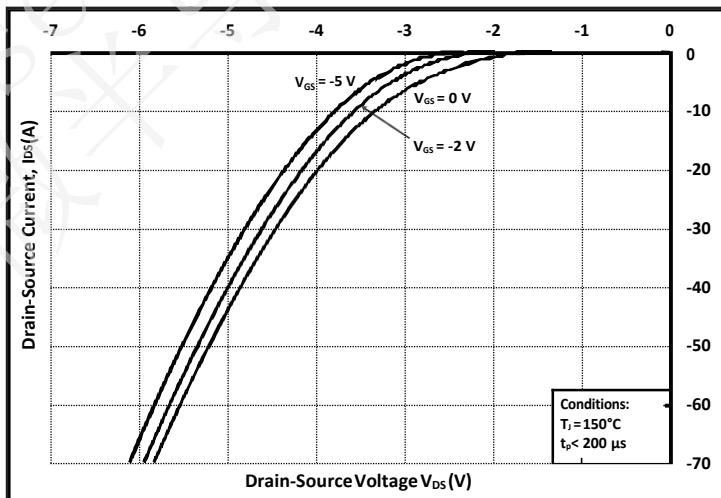


Figure 10. Body Diode Characteristic at 150°C

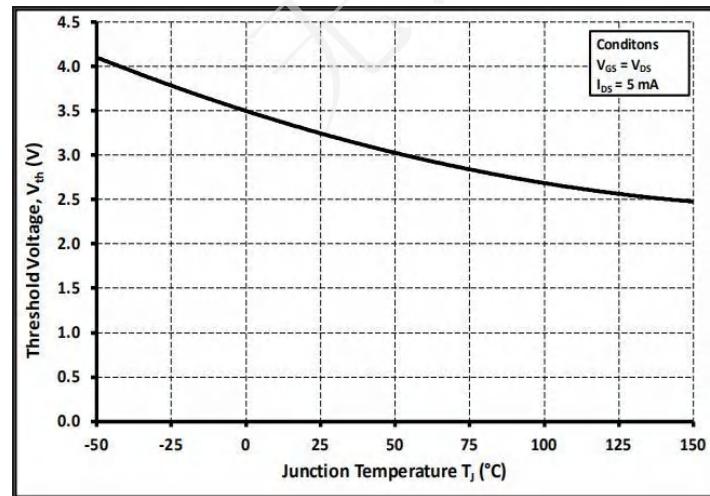


Figure 11. Threshold Voltage vs. Temperature

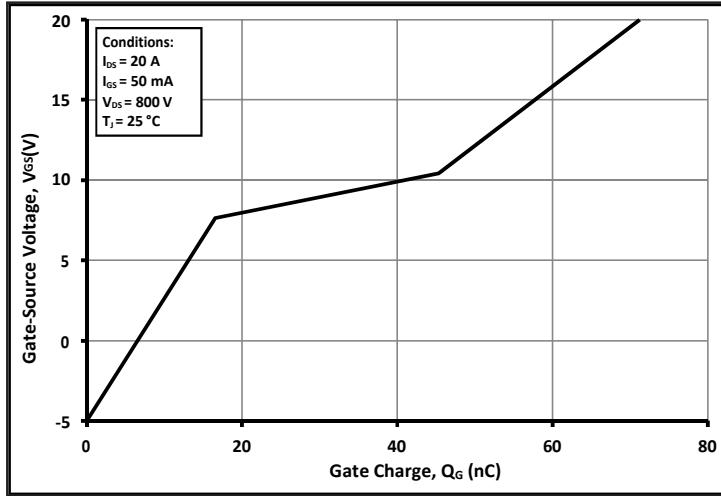


Figure 12. Gate Charge Characteristics



Typical Performance

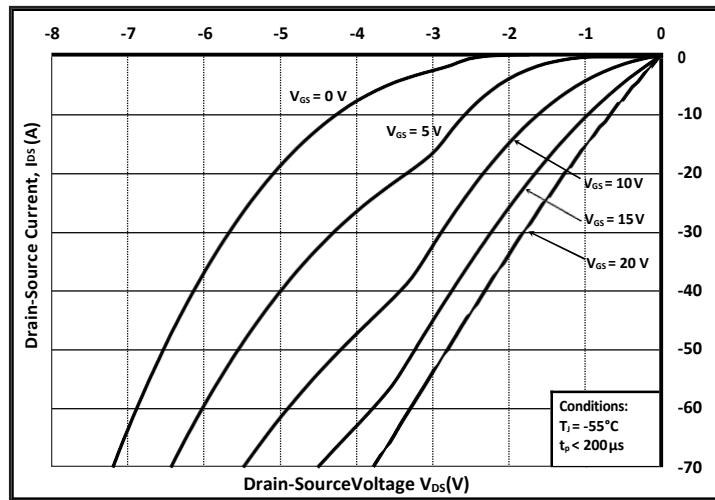


Figure 13. 3rd Quadrant Characteristic at -55°C

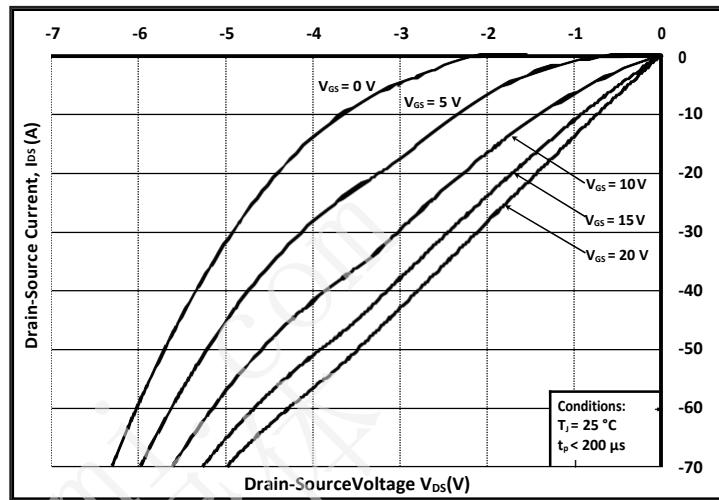


Figure 14. 3rd Quadrant Characteristic at 25°C

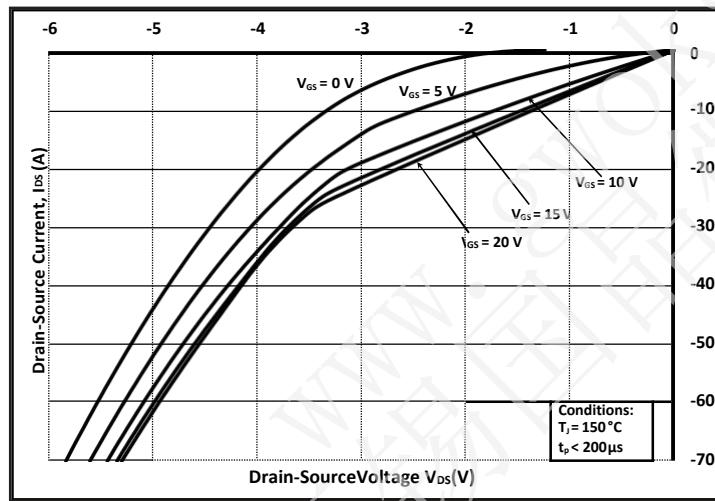


Figure 15. 3rd Quadrant Characteristic at 150°C

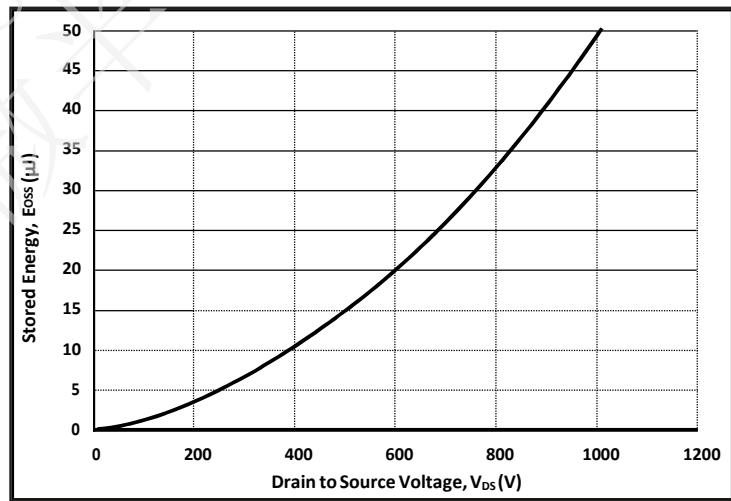


Figure 16. Output Capacitor Stored Energy

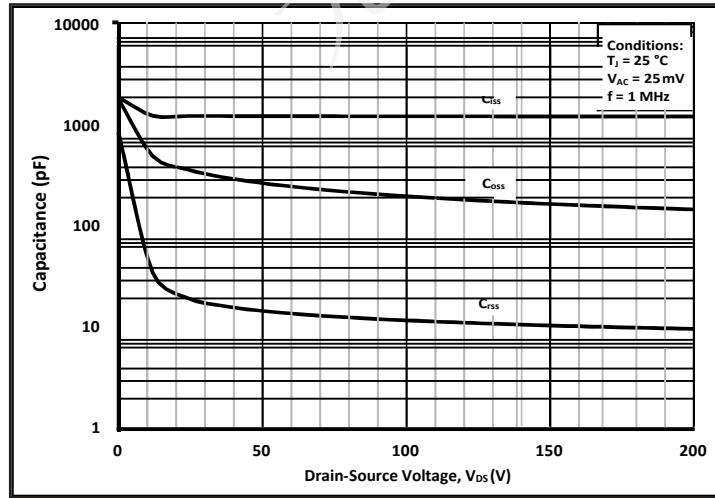


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

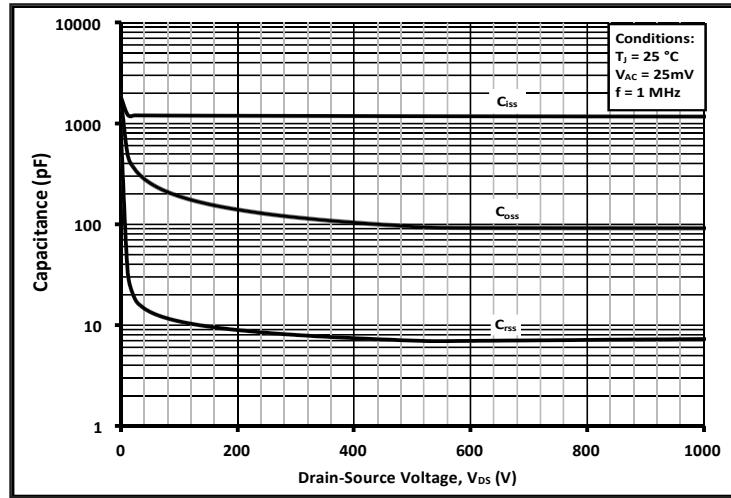


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 1000V)



Typical Performance

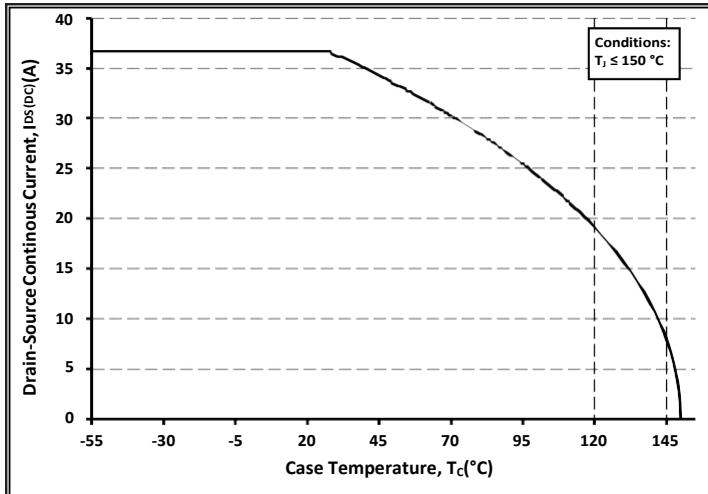


Figure 19. Continuous Drain Current Derating vs.
Case Temperature

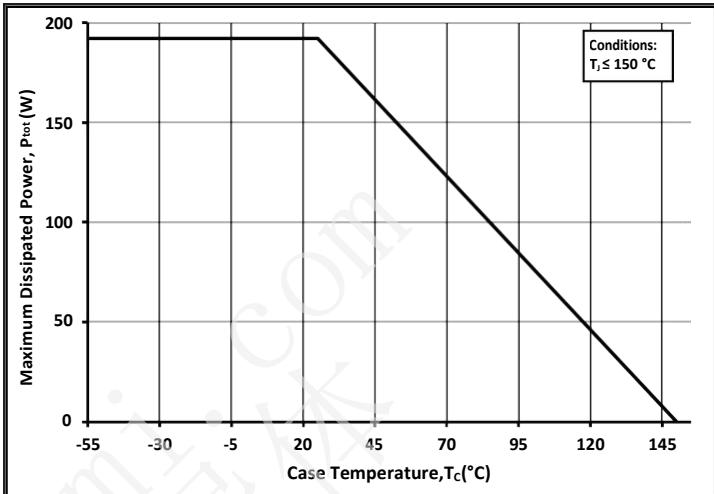


Figure 20. Maximum Power Dissipation Derating vs.
Case Temperature

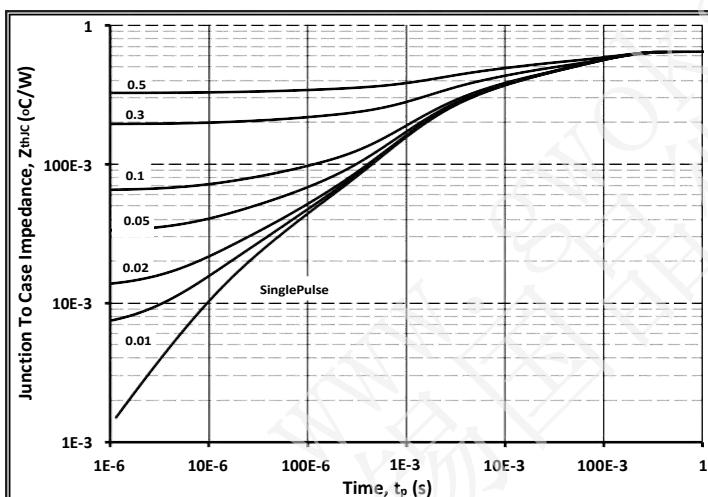


Figure 21. Transient Thermal Impedance
(Junction - Case)

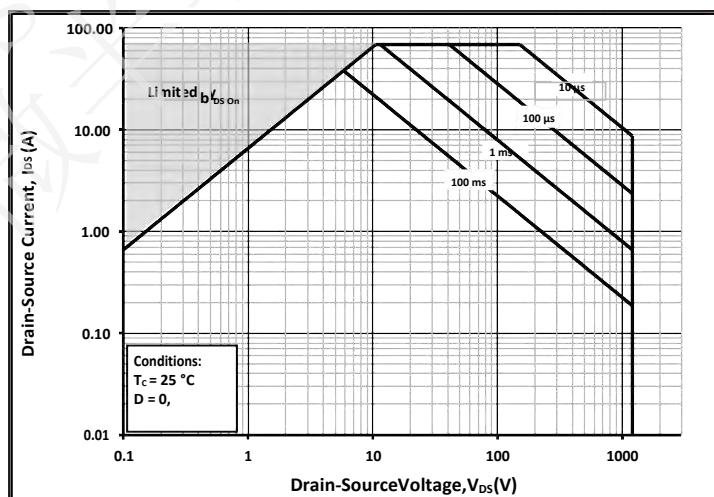


Figure 22. Safe Operating Area

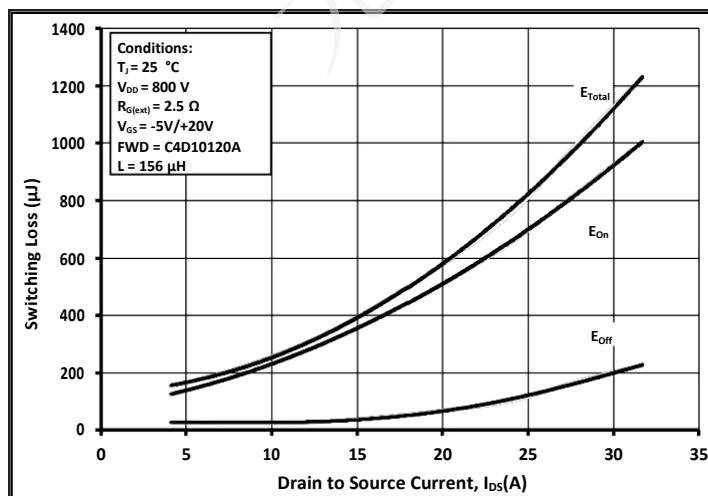


Figure 23. Clamped Inductive Switching Energy vs.
Drain Current ($V_{DD} = 800V$)

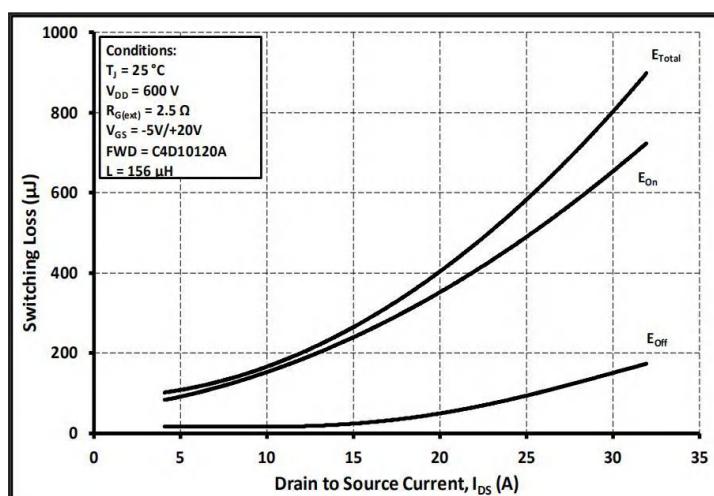


Figure 24. Clamped Inductive Switching Energy vs.
Drain Current ($V_{DD} = 600V$)



Typical Performance

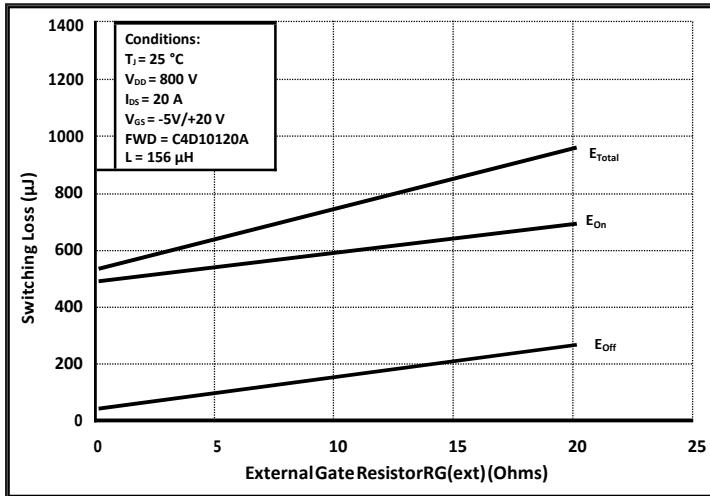


Figure 25. Clamped Inductive Switching Energy vs. $R_{G(\text{ext})}$

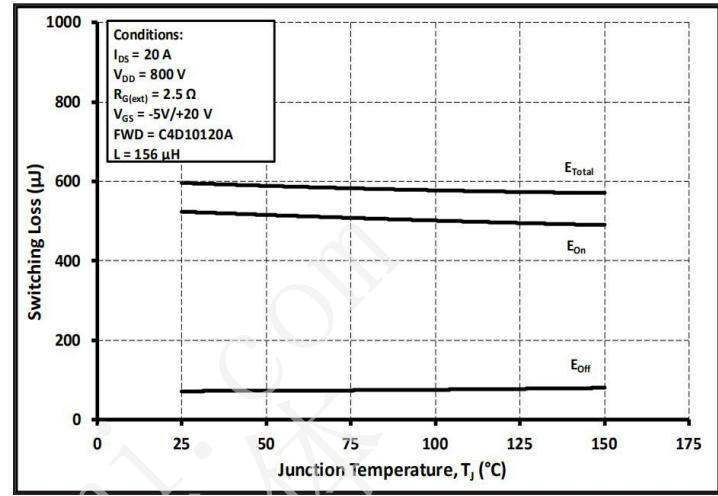


Figure 26. Clamped Inductive Switching Energy vs. Temperature

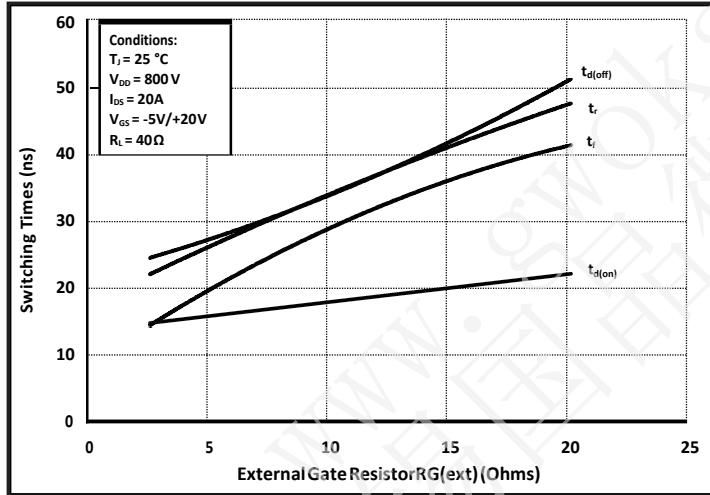


Figure 27. Switching Times vs. $R_{G(\text{ext})}$

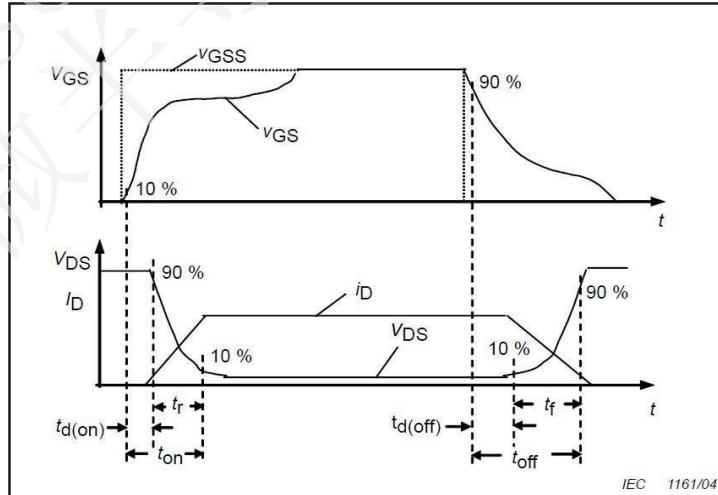


Figure 28. Switching Times Definition

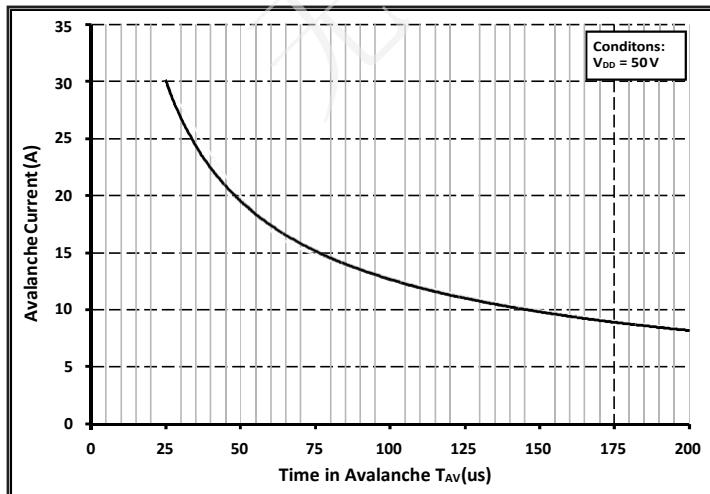


Figure 29. Single Avalanche SOA curve



Test Circuit Schematic

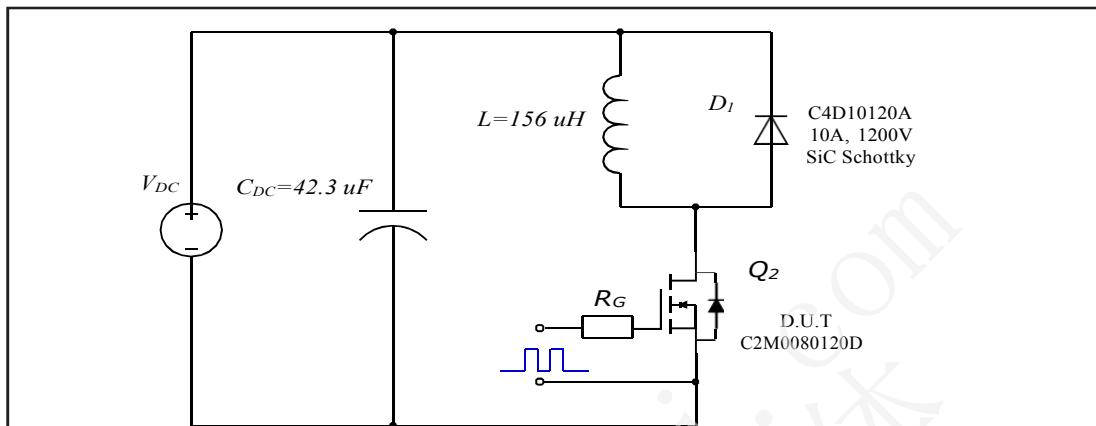


Figure 30. Clamped Inductive Switching Waveform Test Circuit

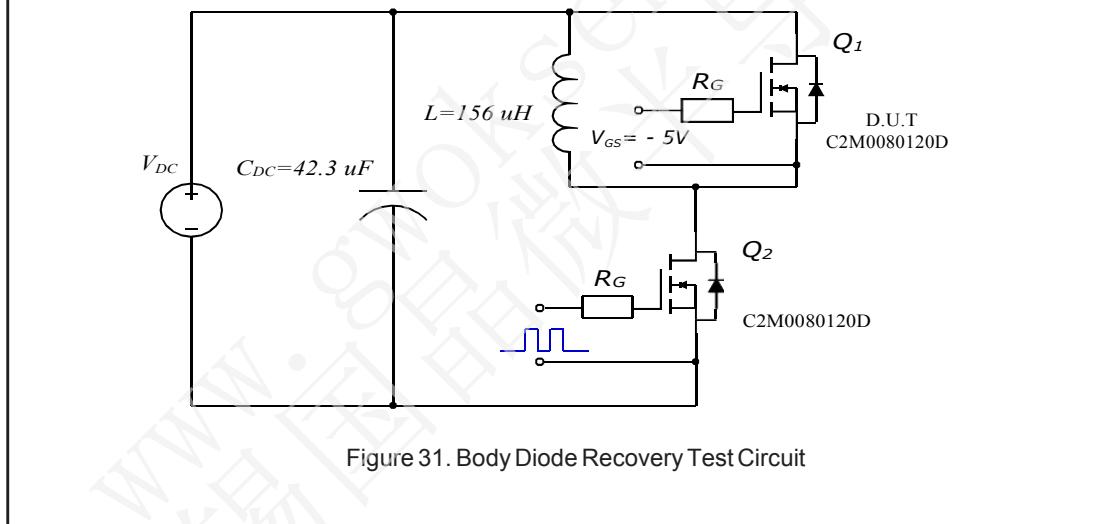


Figure 31. Body Diode Recovery Test Circuit

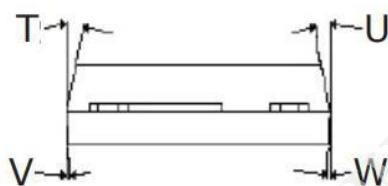
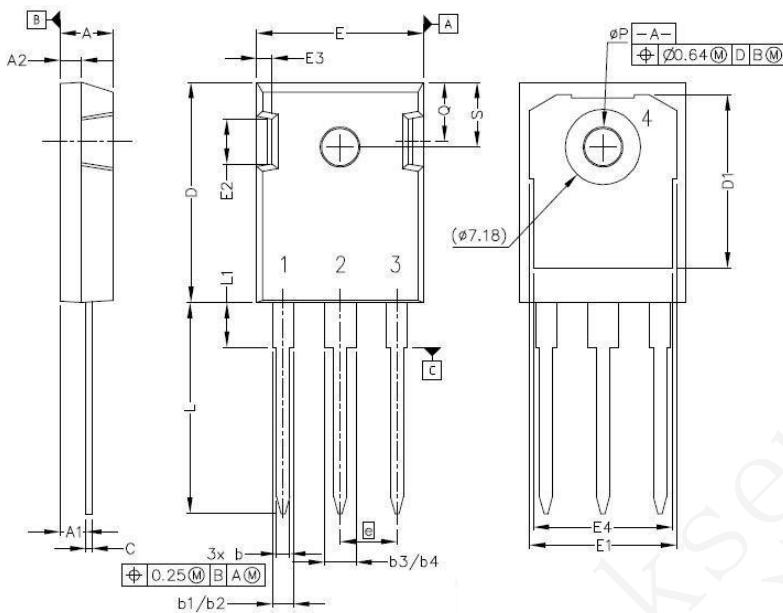
ESD Ratings

| ESD Test | Total Devices Sampled | Resulting Classification |
|----------|--------------------------|--------------------------|
| ESD-HBM | All Devices Passed 1000V | 2 (>2000V) |
| ESD-MM | All Devices Passed 400V | C (>400V) |
| ESD-CDM | All Devices Passed 1000V | IV (>1000V) |



Package Dimensions

Package TO-247-3

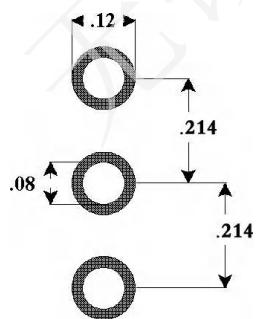


Pinout Information:

- Pin 1 = Gate
- Pin 2, 4 = Drain
- Pin 3 = Source

| POS | Inches | | Millimeters | |
|-----|----------|------|-------------|-------|
| | Min | Max | Min | Max |
| A | .190 | .205 | 4.83 | 5.21 |
| A1 | .090 | .100 | 2.29 | 2.54 |
| A2 | .075 | .085 | 1.91 | 2.16 |
| b | .042 | .052 | 1.07 | 1.33 |
| b1 | .075 | .095 | 1.91 | 2.41 |
| b2 | .075 | .085 | 1.91 | 2.16 |
| b3 | .113 | .133 | 2.87 | 3.38 |
| b4 | .113 | .123 | 2.87 | 3.13 |
| c | .022 | .027 | 0.55 | 0.68 |
| D | .819 | .831 | 20.80 | 21.10 |
| D1 | .640 | .695 | 16.25 | 17.65 |
| D2 | .037 | .049 | 0.95 | 1.25 |
| E | .620 | .635 | 15.75 | 16.13 |
| E1 | .516 | .557 | 13.10 | 14.15 |
| E2 | .145 | .201 | 3.68 | 5.10 |
| E3 | .039 | .075 | 1.00 | 1.90 |
| E4 | .487 | .529 | 12.38 | 13.43 |
| e | .214 BSC | | 5.44 BSC | |
| N | 3 | | 3 | |
| L | .780 | .800 | 19.81 | 20.32 |
| L1 | .161 | .173 | 4.10 | 4.40 |
| ØP | .138 | .144 | 3.51 | 3.65 |
| Q | .216 | .236 | 5.49 | 6.00 |
| S | .238 | .248 | 6.04 | 6.30 |
| T | 9° | 11° | 9° | 11° |
| U | 9° | 11° | 9° | 11° |
| V | 2° | 8° | 2° | 8° |
| W | 2° | 8° | 2° | 8° |

Recommended Solder Pad Layout



TO-247-3

| Part Number | Package | Marking |
|--------------|----------|-------------|
| GC2M0080120D | TO-247-3 | GC2M0080120 |